

Panel Discussion on V&V and Testing in the FPGA Development Process

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Safety Life Cycle of FPGA-based Application (IEC 62566)





V&V techniques

- → Documents Review
- → Failure and Mode Effect Analysis (FMEA)
- → Static Code Analysis and Code Review
- → HDL Code Functional Testing
- → Logic Level Simulation, Timing Simulation and Static Timing Analysis (for FPGA Electronic Design)
- → Reports Review of Synthesis, Place and Route, Bitstream Generation (for FPGA Electronic Design)
- → Fault Insertion Testing (FIT) for the platform level
- → Integration Testing, Validation Testing



Static Code Analysis and Code Review

Tools

Aldec ALINT Mentor Graphics HDL Designer







Functional Testing of RTL





Logic Level Simulation, Timing Simulation



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Static Timing Analysis

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- **1. Analysis of the fault:**
 - To define the module
 - To define the unit
 - To define the symptom



Test Case RID	Unit	Test descriptor detectable symptom	Chassis config'n	Insertion required	Module's MODE	Auto'd Test
FIT.DOM.01	PS	IO.PS VCCINT 1.2V lost.	DOM	open cct	RUN, STARTUP	manual
FIT.DOM.2	PS	IO.PS 3.3v lost	DOM	open cct	RUN, STARTUP	manual
FIT.DOM.3	PS	IO.PS VCCA 2.5v lost.	DOM	open cct	RUN, STARTUP	manual
FIT.DOM.4	PS	IO.PS 2.5v BANK5 lost	DOM	open cct	RUN, STARTUP	manual



- **2. Unit circuit analysis:**
 - To define the element of the unit (VCCA 2.5V)
 - To define the action on the element (VCCA 2.5V <u>Lost</u>)
 - To define the method of the fault realization in scheme







- **3. Requirements to tool for FIT:**
- Making multiple faults at the same time
- Monitoring the changes
 - Representativity
 - Ergonomic design



FIT Panel



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4. Implementation FIT hardware:

- Fault insertion (soldering)
- FIT Panel connection to the module









Analysis results of module self-diagnostics

IO.PS VCCINT 1.2V Lost



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39 Injected faults for Logic Module

Each power supply: loss / high / low
Clock failure (A,B,C), etc.



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Integration and Validation testing: DAS on the base of NI PXI controller and LabView

Data Acquisition System





Expected issues to discuss: General approach to organize V&V

- → Completeness and adequacy of the used techniques and tools set
- → Requirement management and tracing
- → Coverage criteria
- → Tests automation approach
- → FIT for the FPGA chip
- → Best practices
- → Experience transfer from non-safety IT industry: focus on Project Management and Human Factor, agile methodologies etc.



Expected issues to discuss:

Formal verification and Static Code Analysis methods

- → Any relevant experience
- → Models and specification which can be useful
- → Model checking approach
- → Relevant Static Code Analysis methods
- → Tools for Static Code Analysis available at the market



Thank you for your attention!

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